

Title: METHOD AND APPARATUS FOR MEASUREMENT OF THIN FILMS  
AND RESIDUES ON SEMICONDUCTOR SUBSTRATES

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Docket No: LAM2P466 App. No: 10/810,209

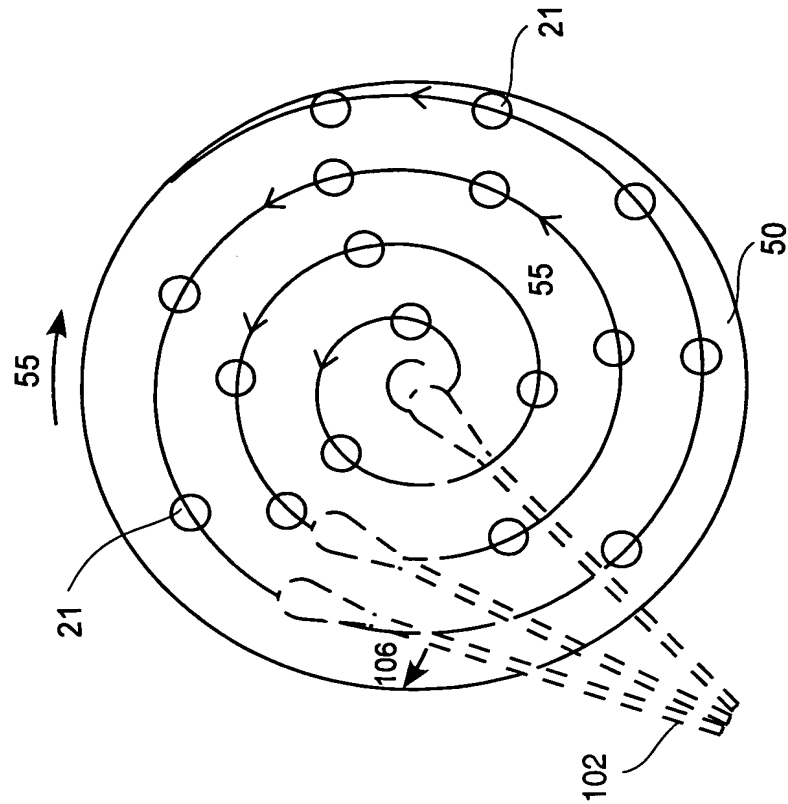


FIG. 4B

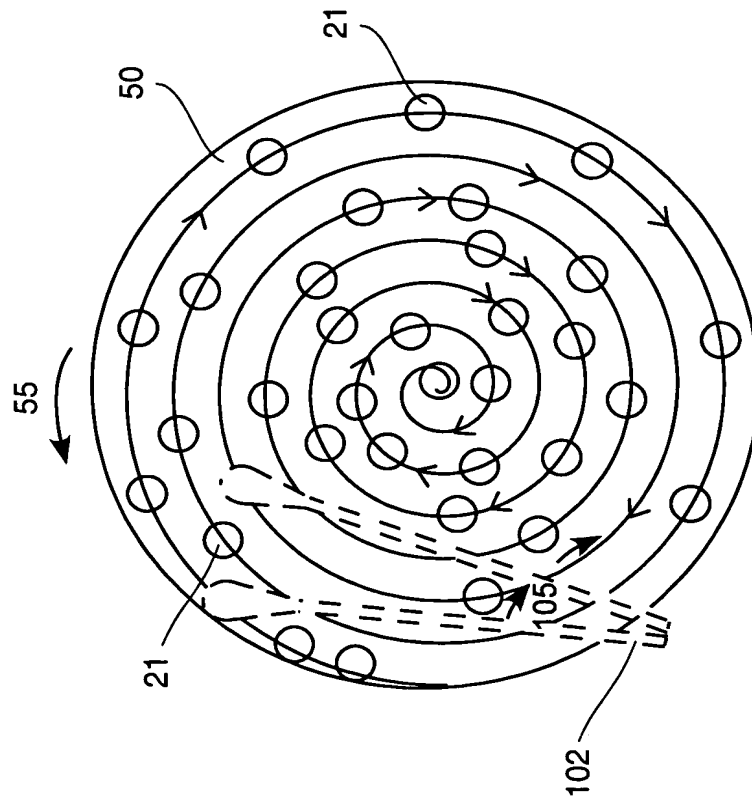


FIG. 4A